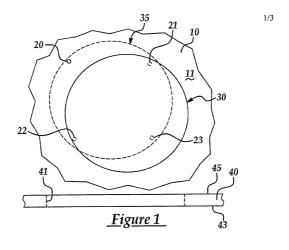
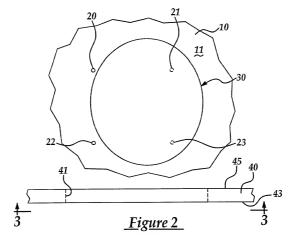
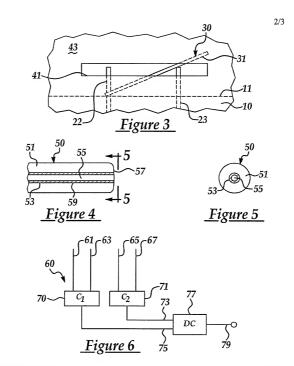
Inventor(s): Chen, et al Serial No.: To Be Assigned Filed: Herewith

For: Microchip Fabrication Chamber Wafer Detection Attorney Docket No.: 67,200-662





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WAFER STATUS	P1	P2	P3	P4	FAULT
MISSING/BROKEN	0	0	0	0	1
MISPOSITIONED	0	X	X	X	1
MISPOSITIONED	X	0	X	X	1
MISPOSITIONED	X	X	0	X	1
MISPOSITIONED	X	X	X	0	1
PROPER	1	1	1	1	0

Figure 7

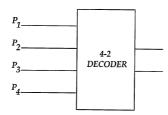
Inventor(s): Chen, et al Serial No.: To Be Assigned Filed: Herewith

For: Microchip Fabrication Chamber Wafer Detection
Attorney Docket No.: 67,200-662

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WAFER STATUS	C1	C2	DC
BROKEN/MISSING	0	0	1
MISPOSITIONED	0	1	1
	1	0	1
PROPER	1	1	0

Figure 8



<u>Figure 9</u>

WAFER STATUS	P1	P2	P3	P4	FAULT
MISSING/BROKEN	0	0	0	0	1/1
MISPOSITIONED	0	0	X	X	1/0
(OFF 2 PINS)	İ				1
MISPOSITIONED	0	1	1	1	0/1
(OFF 1 PIN)				_	7.
MISPOSITIONED	X	0	0	X	1/0
(OFF 2 PINS)	1				7
MISPOSITIONED	1	0	1	1	0/1
(OFF 1 PIN1)				_	7-
MISPOSITIONED	X	X	0	0	1/0
(OFF 2 PINS)	1	İ			7.
MISPOSITIONED	1	1	0	1	0/1
(OFF 1 PIN)					1 7-
MISPOSITIONED	0	X	X	0	1/0
(OFF 2 PINS)		l			7.
MISPOSITIONED	1	1	1	0	0/1
(OFF 1 PIN)	Ι.				-,-
PROPER	1	1	1	1	0/0

Figure 10